

				Doc. # Number (Optional) NEC WNZ-2665		Application Number 10/822,374	
				Applicant(s) OHKUBO et al.			
				Filing Date April 12, 2004		Group Art Unit 2651 2627	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/ND/		6,449,110	9.10.02	DeGROAT et al.	360	46	
/ND/		6,198,587	3.6.01	HAYASHI	360	65	
U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/ND/		2002/0154434	10.24.02	SATO et al.	360	65	
/ND/		2002/0012185	1.31.02	SAWAGUCHI et al.	360	46	
FOREIGN PATENT DOCUMENTS							
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
/ND/	WO 00/22620	4.20.00	PCT	G11B	20/10		
/ND/	1 160 785	12.5.01	EPO	G11B	20/10		
/ND/	09-259543	3.10.97	JAPAN (w/abstract)	G11B	20/14		
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
/ND/		"A New Method to Evaluate Quality for Systems to which PRML is Applied", Nagai et al., Optical Memory and Optical Data Storage Topical Meeting, 2002, pgs. 365-367					
/ND/		"Optimization of Write Strategy in a PRML System for High Density Recording", Ohkubo et al., Optical Memory and Optical Data Storage Topical Meeting, 2002, pgs. 425-427					
EXAMINER				DATE CONSIDERED			
/Nathan Danielson/				05/13/2008			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							